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PATENT
Docket No. 356952000304

CERTIFICATE OF MAILING BY "EXPRESS MAIL"

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Barbara M. Weathersby
Barbara M. Weathersby

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In the application of:

Kurt E. PETERSEN et al.

Serial No.: 09/928,194

Filing Date: August 11, 2001

For: SINGLE CRYSTAL SILICON SENSOR
WITH HIGH ASPECT RATIO AND
CURVILINEAR STRUCTURES AND
ASSOCIATED METHOD

Examiner: D. Kang

Group Art Unit: 2811

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**SUPPLEMENTAL INFORMATION DISCLOSURE
STATEMENT UNDER 37 C.F.R. § 1.97 AND § 1.98**

Assistant Commissioner for Patents
Washington, D.C. 20231

Dear Sir:

Pursuant to 37 C.F.R. § 1.97 and § 1.98, Applicants submit for consideration in the above-identified application the documents listed on the attached Form PTO-1449. Copies of the documents are also submitted herewith. The Examiner is requested to make these documents of record.

04/18/2003 EHAILE1 00000032 031952 09928194

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This Supplemental Information Disclosure Statement is submitted:

- Within three months of the application filing date or before mailing of a first Office Action on the merits; accordingly, no fee or separate requirements are required.
- After receipt of a first Office Action on the merits but before mailing of a final Office Action or Notice of Allowance.
 - A fee is required. A check in the amount of is enclosed.
 - A fee is required. Accordingly, a Fee Transmittal form (PTO/SB/17) is attached to this submission in duplicate.
 - A Certification under 37 C.F.R. § 1.97(e) is provided below; accordingly; no fee is believed to be due.
- After mailing of a final Office Action or Notice of Allowance, but before payment of the issue fee.
 - A Certification under 37 C.F.R. § 1.97(e) is provided below and a check in the amount of is enclosed.
 - A Certification under 37 C.F.R. § 1.97(e) is provided below and a Fee Transmittal form (PTO/SB/17) is attached to this submission in duplicate.

Applicants would appreciate the Examiner initialing and returning the Form PTO-1449, indicating that the information has been considered and made of record herein.

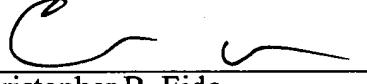
The information contained in this Supplemental Information Disclosure Statement under 37 C.F.R. § 1.97 and § 1.98 is not to be construed as a representation that: (i) a complete search has been made; (ii) additional information material to the examination of this application does

not exist; (iii) the information, protocols, results and the like reported by third parties are accurate or enabling; or (iv) the above information constitutes prior art to the subject invention.

In the unlikely event that the transmittal letter is separated from this document and the Patent Office determines that an extension and/or other relief is required, Applicants petition for any required relief including extensions of time and authorize the Assistant Commissioner to charge the cost of such petitions and/or other fees due in connection with the filing of this document to Deposit Account No. 03-1952 referencing 356952000304. However, the Assistant Commissioner is not authorized to charge the cost of the issue fee to the Deposit Account.

Dated: April 15, 2003

Respectfully submitted,

By: 

Christopher B. Eide
Registration No. 48,375

Morrison & Foerster LLP
755 Page Mill Road
Palo Alto, California 94304-1018
Telephone: (650) 813-5720
Facsimile: (650) 494-0792

Form PTO-1449 INFORMATION DISCLOSED OR MADE OF RECORD IN AN APPLICATION (Use several sheets if necessary)		Docket Number 356952000304	Application Number 09/928,194
		Applicant	Kurt E. PETERSEN et al.
		Filing Date August 11, 2001	Group Art Unit 2811
		Mailing Date April 15, 2003	

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U.S. PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Name	Class	Subclass	Filing Date If 21 Appropriate
1.	03/28/1995	5,400,824	Gschwendtner et al.				

FOREIGN PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Country	Class	Subclass	Translation YES NO
	2.	07/23/1992	41 01 575 <u>Esp@ce</u> summary of document only, located at <<http://gb.esp@c ent.com>>.	DE			x
	3.	11/23/1995	44 17 251 <u>Esp@ce</u> summary of document only, located at <<http://gb.esp@c ent.com>>.	DE			x
	4.	01/04/1996	44 22 942 <u>Esp@ce</u> summary of document only, located at <<http://gb.esp@c ent.com>>.	DE			x

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EXAMINER: Initial if citation considered, whether or not the citation conforms with MPEP 609. Draw a line through the citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.

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Form PTO-1449 INFORMATION DISCLOSURE & CITATION IN AN APPLICATION <i>(Use several sheets if necessary)</i>					Docket Number 356952000304	Application Number 09/928,194
Applicant					Kurt E. PETERSEN et al.	
Filing Date August 11, 2001					Group Art Unit 2811	
Mailing Date April 15, 2003						

5.	08/20/1987	62190775 <u>Esp@ce</u> summary of document only, located at <<http://gb.esp@c ent.com>>.	JP			X	
6.	04/01/1999	WO 99/16096	WIPO				

OTHER DOCUMENTS*(including author, title, Date, Pertinent Pages, Etc.)*

Examiner Initials	Ref. No.	Title
	7.	Analog Devices, (1996). "Monolithic Accelerometer With Signal Conditioning," Analog Devices ADXL50 Datasheet Specifications. pp. 1-16.
	8.	Noworolski, J. M. et al. (1996). "Process for In-Plane and Out-of-Plane Single-Crystal-Silicon Thermal Microactuators," <i>Sensors and Actuators</i> 55(1):65-69.
	9.	Seidel, H. et al. (1990). "Anisotropic Etching of Crystalline Silicon in Alkaline Solutions: I. Orientation Dependence and Behavior of Passivation Layers," <i>J. Electropchemica Soc.</i> 137(11):3612-3626.
	10.	Seidel, H. et al. (1990). "Anisotropic Etching of Crystalline Silicon in Alkaline Solutions: II. Influence of Dopants," <i>J. Electropchemica Soc.</i> 137(11):3626-3632.

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